| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|----------|------|--|--------------------|---------------------|---------|------------------|
| L1 | 6 | (test adj element adj group) same transistor and lithography | US-PGPUB; USPAT | OR | ON | 2005/08/29 10:52 |
| L5 | 53 | test and parameter and transistor same lithography same interconnect | US-PGPUB; USPAT | OR | ON | 2005/08/29 10:59 |
| L6 | 8 | (test adj element adj group) same transistor and interconnect | US-PGPUB; USPAT | OR | ON | 2005/08/29 10:53 |
| L9 | 65 | parametric same performance same transistor | US-PGPUB; USPAT | OR | ON | 2005/08/29 10:59 |
| L10 | 23 | parametric same performance same transistor and interconnect | US-PGPUB; USPAT | OR | ON | 2005/08/29 10:59 |